RefMat No   43

COMAR

Included in
COMAR Database:
Green 1 --> YES
Blue 0 --> NO

Category 1	Nano Objects / Nanopart
Category 2	
Category 3	
Category 4	
Category 5	

Type_of_RefMat: **RM**

Name of RM: Silica Contamination Standard (SCS)

Description

Silica Contamination Standards
Silica Spheres on Si wafer; used to calibrate instruments which size and detect particles on the surface of bare silicon wafers

Link   http://www.vlsistandards.com/products/contamination/silica.asp?SID=24

Certified Qantities

sphere diameter	MeanValue	**100**	nm	Uncertainty
sphere diameter	MeanValue	**126**	nm	Uncertainty
sphere diameter	MeanValue	**150**	nm	Uncertainty
sphere diameter	MeanValue	**180**	nm	Uncertainty
size distribution	MeanValue		nm	Uncertainty

Calibration of	**Size distribution of particles**
Calibration of	**Particle counters**
Calibration of	
Calibration of	
Calibration of	

Characterised by
Characterised by
Characterised by
Characterised by
Characterised by

2 Provider   **Provider No   3**

Provider No 3	Web address http://www.vlsistandards.com
Provider **VLSI Standards, Inc.**	

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